

Search Notes

Application/Control No.

10/711,772

Examiner

/BINH K. TIEU/

Applicant(s)/Patent under
Reexamination

CHARYTAN ET AL.

Art Unit

2614

SEARCHED

Class	Subclass	Date	Examiner
379	111	12/14/2007	BKT
	114.01		
	114.15		
	114.17		
	114.2		
	91.01		
	93.02-04		
235	380, 487		
	490-492		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST DATABASES SEARCH	12/6/2007	BKT
WEST DATABASES SEARCH	12/10/2007	BKT
WEST DATABASES SEARCH	12/11/2007	BKT